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|-----------------------------------|--|---------------------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. 10/562,994 | Applicant(s)/Patent Under Reexamination HOHENTHANNER ET AL. | |
| | | Examiner STEPHEN YANCHUK | Art Unit 4131 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------|----------------|
| * | A | US-2002/0064593 A1 | 05-2002 | Kohler et al. | 427/115 |
| * | B | US-2005/0281981 A1 | 12-2005 | Puffer et al. | 428/137 |
| * | C | US-2002/0172850 | 11-2002 | Asano et al. | 429/33 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------------|----------------|
| | N | JP 2001160405 A | 06-2001 | Japan | YOSHITAKE et al. | H01M 08/02 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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